

Description

The SIRA01DP-T1-GE3 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

 $V_{DS} = -30V I_{D} = -90A$

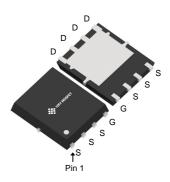
 $R_{DS(ON)}$ < 4.5 m Ω V_{GS} =-10V

Application

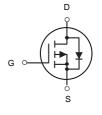
Battery protection

Load switch

Uninterruptible power supply



DFN5X6-8L



P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
SIRA01DP-T1-GE3	DFN5X6-8L	HXY MOSFET	5000

Absolute Maximum Ratings (Tc=25 ℃ unless otherwise noted)

Symbol	Parameter	Rating	Units
VDS	Drain-Source Voltage	-30	V
Vgs	Gate-Source Voltage	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	-90	А
Io@Tc=100°C	Continuous Drain Current, V _{GS} @ 10V ¹	-57	А
Ірм	Pulsed Drain Current ²	-360	А
EAS	Single Pulse Avalanche Energy ³	125	mJ
P _D @T _C =25°C	Total Power Dissipation⁴	60	W
Tstg	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	55	°C/W
Rыс	Thermal Resistance Junction-Case ¹	2.08	°C/W



Electrical Characteristics (T_J = 25°C, unless otherwise noted)

Parameter		Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Drain-Source Breakdown Voltage		V _{(BR)DSS}	V _{GS} = 0V, I _D = -250µA	-30	-	-	V	
Gate-body Leakage current		Igss	V _{DS} = 0V, V _{GS} = ±20V	-	-	±100	nA	
Zero Gate Voltage Drain Current	TJ=25°C	lane	V _{DS} = -30V, V _{GS} = 0V	-	-	-1	μA	
	T _J =100°C	IDSS	VDS = -30V, VGS = 0V	-	-	-100		
Gate-Threshold Voltage		V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-1.0	-1.6	-2.5	V	
Daire Communication of		R _{DS(on)}	V _{GS} = -10V, I _D = -30A	-	3.5	4.5	0	
Drain-Source On-Resistance	; ·	KDS(on)	V _{GS} = -4.5V, I _D = -15A	-	4.8	6.2	mΩ	
Forward Transconductance ⁴		g fs	V _{DS} = -10V, I _D = -30A	-	90	-	S	
Input Capacitance		C _{iss}		-	5070	-	pF	
Output Capacitance		Coss	$V_{DS} = -15V, V_{GS} = 0V,$ f = 1MHz	-	695	-		
Reverse Transfer Capacitance		Crss		-	580	-		
Gate resistance	Gate resistance		f=1MHz	-	4	-	Ω	
Total Gate Charge		Qg		-	146	-		
Gate-Source Charge		Q _{gs}	$V_{GS} = -10V, V_{DS} = -15V,$ $I_{D} = -30A$	-	21.5	-	nC	
Gate-Drain Charge		Q _{gd}		-	39	-		
Turn-On Delay Time		t _{d(on)}		-	23	-	ns	
Rise Time		tr	$V_{GS} = -10V, V_{DD} = -15V,$	-	15	-		
Turn-Off Delay Time		t _{d(off)}	$R_G = 3\Omega, I_D = -30A$	-	129	-		
Fall Time		t _f		-	28	-		
Diode Forward Voltage ⁴		VsD	I _S = -30A, V _{GS} = 0V	-	-	-1.2	V	
Continuous Source Current	T _C =25°C	Is	-	-	-	-90	Α	

Note:

- 1. Repetitive rating, pulse width limited by junction temperature $T_{J(MAX)}$ =150 $^{\circ}$ C
- 2. The EAS data shows Max. rating . The test condition is V_{DD} = -25V, V_{GS} = -10V, L= 0.1mH, I_{AS} = -50A
- 3. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper, The value in any given application depends on the user's specific board design.

Typical Characteristics

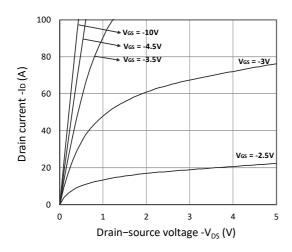


Figure 1. Output Characteristics

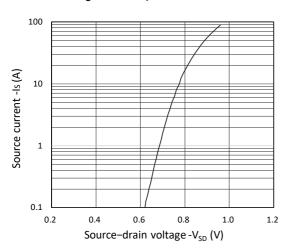


Figure 3. Forward Characteristics of Reverse

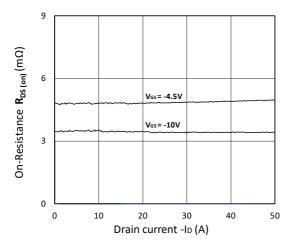


Figure 5. R_{DS(ON)} vs. I_D

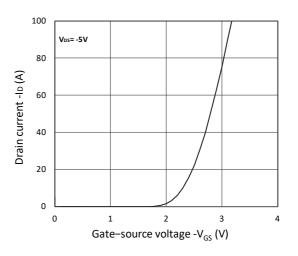


Figure 2. Transfer Characteristics

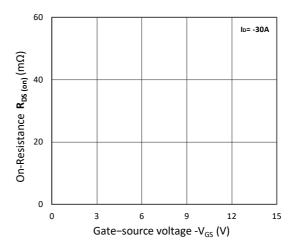


Figure 4. $R_{\text{DS}(\text{ON})}\,$ vs. $V_{\text{GS}}\,$

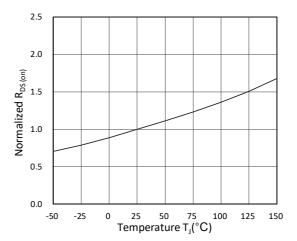


Figure 6. Normalized $R_{\text{DS(on)}}$ vs. Temperature

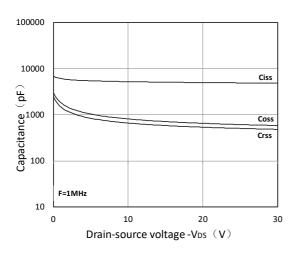


Figure 7. Capacitance Characteristics

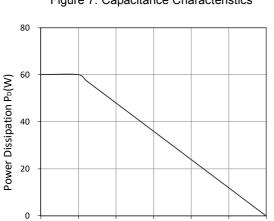


Figure 9. Power Dissipation

75

Case Temperature T_C (°C)

125

150

0

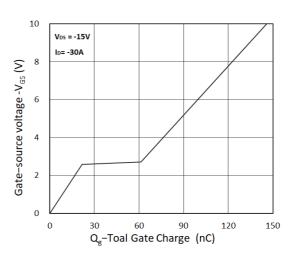


Figure 8. Gate Charge Characteristics

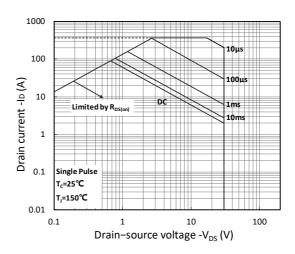


Figure 10. Safe Operating Area

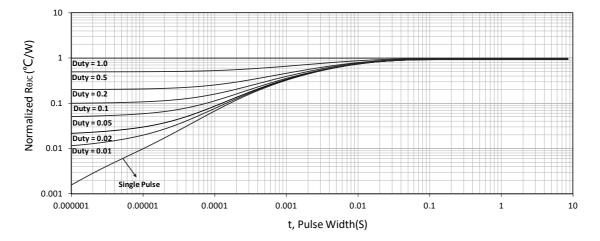


Figure 11. Normalized Maximum Transient Thermal Impedance



Test Circuit

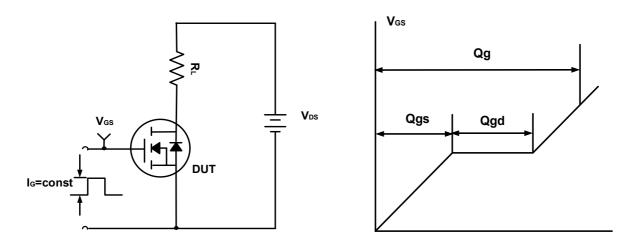


Figure A. Gate Charge Test Circuit & Waveforms

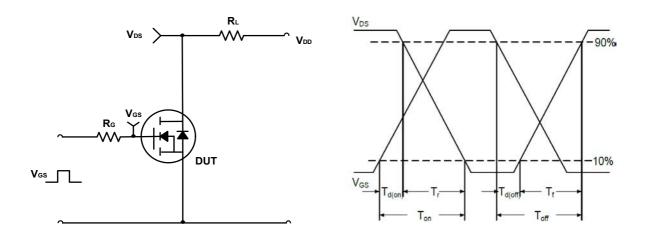


Figure B. Switching Test Circuit & Waveforms

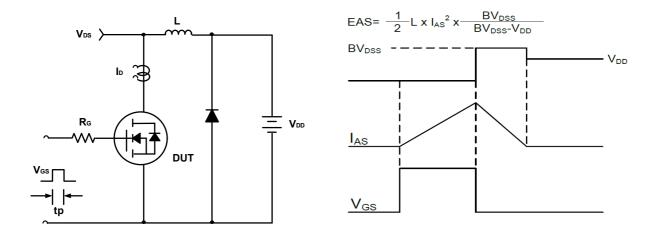
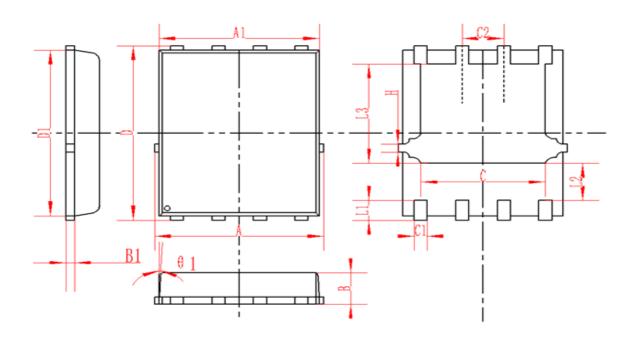


Figure C. Unclamped Inductive Switching Circuit & Waveforms

DFN5X6-8L Package Information



SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
А	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
В	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF		0.010REF			
С	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2		1.27TYP			0.5TYP	
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
Н	0.24	0.25	0.26	0.009	0.010	0.010



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